## Koichiro Saga

## List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/4451412/publications.pdf

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5 papers	24 citations	2 h-index	2272923 4 g-index
5	5	5	20
all docs	docs citations	times ranked	citing authors

#	Article	IF	CITATIONS
1	Behavior of Transition Metals Penetrating Silicon Substrate through SiO <sub>2</sub> and Si <sub>3</sub> N <sub>4</sub> Films by Arsenic Ion Implantation and Annealing. ECS Journal of Solid State Science and Technology, 2015, 4, P131-P136.	1.8	18
2	Depth Profile Analysis of Metals Gettered by Oxide Precipitates in Silicon Substrates. ECS Journal of Solid State Science and Technology, 2017, 6, P231-P234.	1.8	3
3	$\langle i \rangle$ (Invited) $\langle i \rangle$ Metallic Contamination Issues in Advanced Semiconductor Processing. ECS Transactions, 2018, 86, 113-124.	0.5	2
4	(Invited) Metallic Contamination Issues in Advanced Semiconductor Processing. ECS Meeting Abstracts, $2018,  ,  .$	0.0	1
5	Depth Profile Analysis of Metals Gettered By Bulk Micro-Defects (BMDs) in Silicon Substrates. ECS Meeting Abstracts, 2016, , .	0.0	0